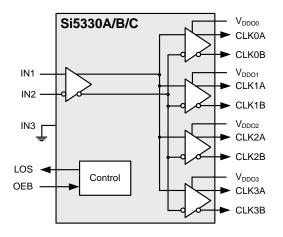
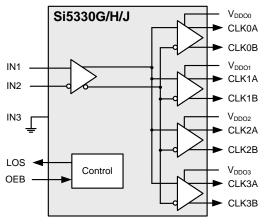
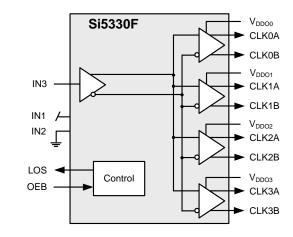
# 1. Functional Block Diagrams Based on Orderable Part Number<sup>\*</sup>



## **1:4 Differential to Differential Buffer**

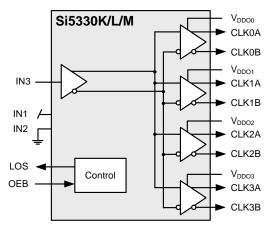
## **1:8 Differential to Single-Ended Buffer**





## 1:8 Single-Ended to Single-Ended Buffer







\*Note: See Table 11 for detailed ordering information.



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# 2. Electrical Specifications

## **Table 1. Recommended Operating Conditions**

 $(V_{DD} = 1.8 \text{ V} -5\% \text{ to } +10\%, 2.5 \text{ V} \pm 10\%, \text{ or } 3.3 \text{ V} \pm 10\%, T_A = -40 \text{ to } 85^{\circ}\text{C})$ 

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Ambient Temperature	T <sub>A</sub>		-40	25	85	°C
Core Supply Voltage			2.97	3.3	3.63	V
	V <sub>DD</sub>		2.25	2.5	2.75	V
			1.71	1.8	1.98	V
Output Buffer Supply Voltage	V <sub>DDOn</sub>		1.4		3.63	V
Note: All minimum and ma Typical values apply		tions are guaranteed a				

## Table 2. DC Characteristics

(V<sub>DD</sub> = 1.8 V –5% to +10%, 2.5 V ±10%, or 3.3 V ±10%, T<sub>A</sub> = –40 to 85°C)

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Core Supply Current	I <sub>DD</sub>	50 MHz refclk	_	10	—	mA
		LVPECL, 710 MHz	_	—	30	mA
		LVDS, 710 MHz	_	—	8	mA
		HCSL, 250 MHz 2 pF load capacitance	_	_	20	mA
Output Buffer Supply Current	I <sub>DDOx</sub>	SSTL, 350 MHz	_	—	19	mA
		CMOS, 50 MHz 15 pF load capacitance	_	_	28	mA
		CMOS, 200 MHz 2 pF load capacitance	_	_	28	mA
		HSTL, 350 MHz		_	19	mA



#### **Table 3. Performance Characteristics**

(V<sub>DD</sub> = 1.8 V –5% to +10%, 2.5 V ±10%, or 3.3 V ±10%, T<sub>A</sub> = –40 to 85°C)

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
CLKIN Loss of Signal Assert Time	t <sub>LOS</sub>		_	2.6	5	μs
CLKIN Loss of Signal De-Assert Time	t <sub>LOS_B</sub>	After initial start-up time has expired	0.01	0.2	1	μs
Input-to-Output Propagation Delay	t <sub>PROP</sub>		_	2.5	4.0	ns
Output-Output Skew	t <sub>DSKEW</sub>	Outputs at same signal format	_	_	100	ps
POR to Output Clock Valid	t <sub>START</sub>	Start-up time for output clocks	_	_	2	ms

Table 4. Input and Output Clock Characteristics (V<sub>DD</sub> = 1.8 V –5% to +10%, 2.5 V ±10%, or 3.3 V ±10%, T<sub>A</sub> = –40 to 85 °C)

Parameter	Symbol	Test Condition	Min	Тур	Мах	Units
Input Clock (AC Coupled I	Differential In	put Clocks on Pin IN1/2)			l	ł
Frequency	f <sub>IN</sub>		5	_	710	MHz
Differential Voltage Swing	V <sub>PP</sub>	710 MHz input	0.4	—	2.4	V <sub>PP</sub>
Rise/Fall Time	t <sub>R</sub> /t <sub>F</sub>	20%-80%	—	—	1.0	ns
Duty Cycle	DC	< 1 ns tr/tf	40	50	60	%
Input Impedance	R <sub>IN</sub>		10	—	_	kΩ
Input Capacitance	C <sub>IN</sub>		_	3.5	—	pF
Input Clock (DC-Coupled S	Single-Ended	Input Clock on Pin IN3)				·
-	4	CMOS	5		200	MHz
Frequency	f <sub>IN</sub>	HSTL, SSTL	5	_	350	MHz
Input Voltage	VI		-0.1	_	VDD	V
Input Voltage Swing (CMOS Standard)		200 MHz, Tr/Tf = 1.3 ns	0.8	—	_	Vpp
Rise/Fall Time	t <sub>R</sub> /t <sub>F</sub>	20%-80%	_	_	4	ns
Duty Cycle	DC	< 2 ns tr/tf	40	50	60	%
Input Capacitance	C <sub>IN</sub>		_	2	_	pF
Output Clocks (Differentia	I)					
-	4	LVPECL, LVDS	5	_	710	MHz
Frequency	fout	HCSL	5	_	250	MHz



## Table 4. Input and Output Clock Characteristics (Continued)

 $(V_{DD} = 1.8 \text{ V} -5\% \text{ to } +10\%, 2.5 \text{ V} \pm 10\%, \text{ or } 3.3 \text{ V} \pm 10\%, \text{ T}_{A} = -40 \text{ to } 85 \text{ °C})$ 

Parameter	Symbol	Test Condition	Min	Тур	Мах	Units
	V <sub>OC</sub>	common mode	_	V <sub>DDO</sub> – 1.45 V	_	V
LVPECL Output Voltage	V <sub>SEPP</sub>	peak-to-peak single- ended swing	0.55	0.8	0.96	V <sub>PP</sub>
	V <sub>OC</sub>	common mode	1.125	1.2	1.275	V
LVDS Output Voltage (2.5/3.3 V)	V <sub>SEPP</sub>	peak-to-peak single- ended swing	0.25	0.35	0.45	V <sub>PP</sub>
	V <sub>OC</sub>	common mode	0.8	0.875	0.95	V
LVDS Output Voltage (1.8 V)	V <sub>SEPP</sub>	peak-to-peak single- ended swing	0.25	0.35	0.45	V <sub>PP</sub>
	V <sub>OC</sub>	common mode	0.35	0.375	0.400	V
HCSL Output Voltage	V <sub>SEPP</sub>	peak-to-peak single- ended swing	0.575	0.725	0.85	V <sub>PP</sub>
Rise/Fall Time	t <sub>R</sub> /t <sub>F</sub>	20%-80%	—	_	450	ps
		CKn < 350 MHz	45	_	55	%
Duty Cycle*	DC	350 MHz < CLKn < 710 MHz	40		60	%
Output Clocks (Single-End	ded)		· · ·			
_		CMOS	5	_	200	MHz
Frequency	fout	SSTL, HSTL	5	_	350	MHz
CMOS 20%-80% Rise/Fall Time	t <sub>R</sub> /t <sub>F</sub>	2 pF load	—	0.45	0.85	ns
CMOS 20%-80% Rise/Fall Time	t <sub>R</sub> /t <sub>F</sub>	15 pF load	_		1.7	ns
CMOS Output Resistance			—	50	_	Ω
SSTL Output Resistance			—	50	_	Ω
HSTL Output Resistance			—	50	—	Ω
	V <sub>OH</sub>	4 mA load	VDDO-0.3	_		V
CMOS Output Voltage	V <sub>OL</sub>	4 mA load		_	0.3	V
	V <sub>OH</sub>	- SSTL-3 VDDOx = 2.97 to	0.45xVDDO+0.41	_	—	V
	V <sub>OL</sub>	3.63 V	—		0.45xVDDO -0.41	V
	V <sub>OH</sub>		0.5xVDDO+0.41	_	_	V
SSTL Output Voltage	V <sub>OL</sub>	SSTL-2 VDDOx = 2.25 to 2.75 V	_		0.5xVDDO- 0.41	V
	V <sub>OH</sub>		0.5xVDDO+0.34	_		V
	V <sub>OL</sub>	SSTL-18 VDDOx = 1.71 to 1.98 V	—	_	0.5xVDDO- 0.34	V



#### Table 4. Input and Output Clock Characteristics (Continued)

Parameter	Symbol	Test Condition	Min	Тур	Max	Units
	V <sub>OH</sub>		0.5xVDDO +0.3		—	V
HSTL Output Voltage	V <sub>OL</sub>	VDDO = 1.4 to 1.6 V	_	_	0.5xVDDO -0.3	V
Duty Cycle <sup>*</sup>	DC		45		55	%
*Note: Input clock has a 50°	% duty cycle.					

 $(V_{DD} = 1.8 \text{ V} - 5\% \text{ to } +10\%, 2.5 \text{ V} \pm 10\%, \text{ or } 3.3 \text{ V} \pm 10\%, \text{ T}_{A} = -40 \text{ to } 85 \text{ °C})$ 

## Table 5. OEB Input Specifications

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Input Voltage Low	V <sub>IL</sub>				0.3 x V <sub>DD</sub>	V
Input Voltage High	V <sub>IH</sub>		0.7 x V <sub>DD</sub>	_	_	V
Input Resistance	R <sub>IN</sub>		20			kΩ

#### Table 6. Output Control Pins (LOS)

 $(V_{DD} = 1.8 \text{ V} - 5\% \text{ to } +10\%, 2.5 \text{ V} \pm 10\%, \text{ or } 3.3 \text{ V} \pm 10\%, T_A = -40 \text{ to } 85 \text{ °C})$ 

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Output Voltage Low	V <sub>OL</sub>	I <sub>SINK</sub> = 3 mA	0	_	0.4	V
Rise/Fall Time 20–80%	t <sub>R</sub> /t <sub>F</sub>	$C_L$ < 10 pf, pull up $\leq$ 1 k $\Omega$	_	_	10	ns

#### Table 7. Jitter Specifications

 $(V_{DD} = 1.8 V - 5\% \text{ to } +10\%, 2.5 V \pm 10\%, \text{ or } 3.3 V \pm 10\%, T_A = -40 \text{ to } 85^{\circ}\text{C})$ 

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Additive Phase Jitter (12 kHz–20 MHz)	t <sub>RPHASE</sub>	0.7 V pk-pk differential input clock at 622.08 MHz with 70 ps rise/fall time	_	0.150	_	ps RMS
Additive Phase Jitter (50 kHz–80 MHz)	t <sub>RPHASEWB</sub>	0.7 V pk-pk differential input clock at 622.08 MHz with 70 ps rise/fall time	_	0.225	_	ps RMS

#### **Table 8. Thermal Characteristics**

Parameter	Symbol	Test Condition	Value	Unit
Thermal Resistance Junction to Ambient	$\theta_{JA}$	Still Air	37	°C/W
Thermal Resistance Junction to Case	θ <sub>JC</sub>	Still Air	25	°C/W



# Table 9. Absolute Maximum Ratings<sup>1,2,3,4,5</sup>

Parameter	Symbol	Test Condition	Value	Unit
DC Supply Voltage	V <sub>DD</sub>		-0.5 to 3.8	V
Storage Temperature Range	T <sub>STG</sub>		-55 to 150	°C
ESD Tolerance		HBM (100 pF, 1.5 kΩ)	2.5	kV
ESD Tolerance		CDM	550	V
ESD Tolerance		MM	175	V
Latch-up Tolerance			JESD78 (	Compliant
Junction Temperature	ТJ		150	°C
Soldering Temperature (Pb-free profile) <sup>5</sup>	T <sub>PEAK</sub>		260	°C
Soldering Temperature Time at T <sub>PEAK</sub> (Pb-free profile) <sup>5</sup>	Τ <sub>Ρ</sub>		20–40	Sec

Notes:

1. Permanent device damage may occur if the Absolute Maximum Ratings are exceeded. Functional operation should be restricted to the conditions as specified in the operational sections of this data sheet. Exposure to maximum rating conditions for extended periods may affect device reliability.

2. 24-QFN package is RoHS compliant.

3. For more packaging information, go to www.silabs.com/support/quality/pages/RoHSInformation.aspx.

4. Moisture sensitivity level is MSL3.

5. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.



## 3. Functional Description

The Si5330 is a low-jitter, low-skew fanout buffer optimized for high-performance PCB clock distribution applications. The device produces four differential or eight single-ended, low-jitter output clocks from a single input clock. The input can accept either a single-ended or a differential clock allowing the device to function as a clock level translator.

## 3.1. $V_{DD}$ and $V_{DDO}$ Supplies

The core  $V_{DD}$  and output  $V_{DDO}$  supplies have separate and independent supply pins allowing the core supply to operate at a different voltage than the I/O voltage levels.

The  $V_{DD}$  supply powers the core functions of the device, which operates from 1.8, 2.5, or 3.3 V. Using a lower supply voltage helps minimize the device's power consumption. The  $V_{DDO}$  supply pins are used to set the output signal levels and must be set at a voltage level compatible with the output signal format.

## 3.2. Loss Of Signal Indicator (LOS)

The input is monitored for a valid clock signal using an LOS circuit that monitors input clock edges and declares an LOS condition when signal edges are not detected over a 1 to 5  $\mu$ s observation period. The LOS pin is asserted "low" when activity on the input clock pin is present. A "high" level on the LOS pin indicates a loss of signal (LOS). The LOS pin must be pulled to VDD as shown in Figure 2.

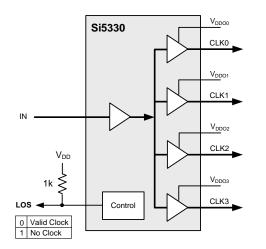


Figure 2. LOS Indicator with External Pull-Up

## 3.3. Output Enable (OEB)

The output enable (OEB) pin allows disabling or enabling of the outputs clocks (CLK0-CLK3). The output enable is logically controlled to ensure that no glitches or runt pulses are generated at the output as shown in Figure 3.

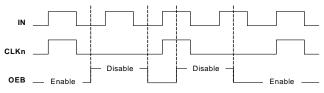


Figure 3. OEB Glitchless Operation

All outputs are enabled when the OEB pin is connected to ground or below the V<sub>IL</sub> voltage for this pin. Connecting the OEB pin to VDD or above the V<sub>IH</sub> level will disable the outputs. Both V<sub>IL</sub> and V<sub>IH</sub> are specified in Table 5. All outputs are forced to a logic "low" when disabled. The OEB pin is 3.3 V tolerant.

## 3.4. Input Signals

The Si5330 can accept single-ended and differential input clocks. See "AN408: Termination Options for Any-Frequency, Any-Output Clock Generators and Clock Buffers—Si5338, Si5334, Si5330" for details on connecting a wide variety of signals to the Si5330 inputs.

## 3.5. Output Driver Formats

The Si5330 supports single-ended output formats of CMOS, SSTL, and HSTL and differential formats of LVDS, LVPECL, and HCSL. It is normally required that the LVDS driver be dc-coupled to the 100  $\Omega$  termination at the receiver end. If your application requires an accoupled 100  $\Omega$  load, contact the applications team for advice. See AN408 for additional information on the terminations for these driver types.

## 3.6. Input and Output Terminations

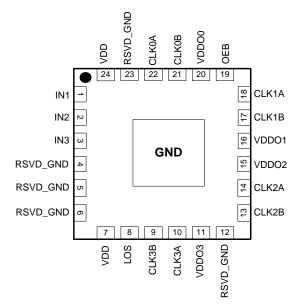
See AN408 for detailed information.

## 4. Ordering the Si5330

The Si5330 can be ordered to meet the requirements of the most commonly-used input and output signal types, such as CMOS, SSTL, HSTL, LVPECL, LVDS, and HSCL. See Figure 1, "Si5330 Functional Block Diagrams," on page 2 and Table 11, "Order Numbers and Device Functionality," on page 14 for specific ordering information.



# 5. Pin Descriptions



**Note:** Center pad must be tied to GND for normal operation.

Pin #	Pin Name	I/O	Signal Type	Description	
1	IN1	I	Multi	Si5330A/B/C/G/H/J Differential Input Devices.	
2	IN2	1	Multi	These pins are used as the differential clock input. IN1 the positive input; IN2 is the negative input. Refer to "AN408: Termination Options for Any-Frequency, Any Output Clock Generators and Clock Buffers—Si5338 Si5334, Si5330" for interfacing and termination details <b>Si5330F/K/L/M Single-Ended Input Devices.</b> These pins are not used. Leave IN1 unconnected and IN2 connected to ground.	
3	IN3	I	Multi	Si5330F/K/L/M Single-Ended Devices. This is the single-ended clock input. Refer to AN408 for interfacing and termination details. Si5330A/B/C/G/H/J Differential Input Devices. This pin is not used. Connect to ground.	
4	RSVD_GND			Ground. Must be connected to system ground.	
5	RSVD_GND			Ground. Must be connected to system ground.	
6	RSVD_GND			Ground. Must be connected to system ground.	



Pin #	Pin Name	I/O	Signal Type	Description	
7	VDD	VDD	Supply	Core Supply Voltage. The device operates from a 1.8, 2.5, or 3.3 V supply. A 0.1 $\mu$ F bypass capacitor should be located very close to this pin.	
8	LOS	0	Open Drain	<b>Loss of Signal Indicator.</b> 0 = CLKIN  present. 1 = Loss of signal (LOS). This pin requires an external $\geq 1 \text{ k}\Omega$ pull-up resistor.	
9	CLK3B	0	Multi	Si5330A/B/C/K/L/M Differential Output Devices. This is the negative side of the differential CLK3 out Refer to AN408 for interfacing and termination detai Leave unconnected when not in use.	
10	CLK3A	0	Multi	Si5330A/B/C/K/L/M Differential Devices. This is the positive side of the differential CLK3 output. Refer to AN408 for interfacing and termination details. Leave unconnected when not in use. Si5330F/G/H/J Single-Ended Devices. This is one of the single-ended CLK3 outputs. Both CLK3A and CLK3B single-ended outputs are in phase. Refer to AN408 for interfacing and termination details. Leave unconnected when not is use.	
11	VDDO3	VDD	Supply	Output Clock Supply Voltage. Supply voltage for CLK3A/B. Use a 0.1 $\mu$ F bypass cap as close as possible to this pin. If CLK3 is not used, this pin must be tied to V <sub>DD</sub> (pin 7 and/or pin 24).	
12	RSVD_GND			Ground. Must be connected to system ground.	
13	CLK2B	0	Multi	Si5330A/B/C/K/L/M Differential Output Devices. This is the negative side of the differential CLK2 output. Refer to AN408 for interfacing and termination details. Leave unconnected when not in use. Si5330F/G/H/J Single-Ended Output Devices. This is one of the single-ended CLK2 outputs. Both CLK2A and CLK2B single-ended outputs are in phase. Refer to AN408 for interfacing and termination details. Leave unconnected when not is use.	



## Table 10. Si5330 Pin Descriptions (Continued)

Pin #	Pin Name	I/O	Signal Type	Description
14	CLK2A	Ο	Multi	Si5330A/B/C/K/L/M Differential Devices. This is the positive side of the differential CLK2 output. Refer to AN408 for interfacing and termination details. Leave unconnected when not in use. Si5330F/G/H/J Single-Ended Devices. This is one of the single-ended CLK2 outputs. Both CLK2A and CLK2B single-ended outputs are in phase. Refer to AN408 for interfacing and termination details. Leave unconnected when not is use.
15	VDDO2	VDD	Supply	Output Clock Supply Voltage. Supply voltage for CLK2A/B. Use a 0.1 $\mu$ F bypass cap as close as possible to this pin. If CLK2 is not used, this pin must be tied to V <sub>DD</sub> (pin 7 and/or pin 24).
16	VDDO1	VDD	Supply	Output Clock Supply Voltage. Supply voltage for CLK1A,B. Use a 0.1 $\mu$ F bypass cap as close as possible to this pin. If CLK1 is not used, this pin must be tied to V <sub>DD</sub> (pin 7 and/or pin 24).
17	CLK1B	0	Multi	Si5330A/B/C/K/L/M Differential Output Devices. This is the negative side of the differential CLK1 output. Refer to AN408 for interfacing and termination details. Leave unconnected when not in use. Si5330F/G/H/J Single-Ended Output Devices. This is one of the single-ended CLK1 outputs. Both CLK1A and CLK1B single-ended outputs are in phase. Refer to AN408 for interfacing and termination details. Leave unconnected when not is use.
18	CLK1A	0	Multi	Si5330A/B/C/K/L/M Differential Devices. This is the positive side of the differential CLK1 output. Refer to AN408 for interfacing and termination details. Leave unconnected when not in use. Si5330F/G/H/J Single-Ended Devices. This is one of the single-ended CLK1 outputs. Both CLK1A and CLK1B single-ended outputs are in phase. Refer to AN408 for interfacing and termination details. Leave unconnected when not is use.
19	OEB	I	CMOS	<b>Output Enable.</b> All outputs are enabled when the OEB pin is connected to ground or below the V <sub>IL</sub> voltage for this pin. Connecting the OEB pin to V <sub>DD</sub> or above the V <sub>IH</sub> level will disable the outputs. Both V <sub>IL</sub> and V <sub>IH</sub> are specified in Table 5. All outputs are forced to a logic "low" when disabled. This pin is 3.3 V tolerant.
20	VDDO0	VDD	Supply	Output Clock Supply Voltage. Supply voltage for CLK0A,B. Use a 0.1 $\mu$ F bypass cap as close as possible to this pin. If CLK2 is not used, this pin must be tied to V <sub>DD</sub> (pin 7 and/or pin 24).



Table 10. Si5330 Pin Description	ons (Continued)
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Pin #	Pin Name	I/O	Signal Type	Description
21	CLK0B	0	Multi	Si5330A/B/C/K/L/M Differential Output Devices. This is the negative side of the differential CLK0 output. Refer to AN408 for interfacing and termination details. Leave unconnected when not in use. Si5330F/G/H/J Single-ended Output Devices. This is one of the single-ended CLK0 outputs. Both CLK0A and CLK0B single-ended outputs are in phase. Refer to AN408 for interfacing and termination details. Leave unconnected when not is use.
22	CLK0A	0	Multi	Si5330A/B/C/K/L/M Differential Devices. This is the positive side of the differential CLK0 output. Refer to AN408 for interfacing and termination details. Leave unconnected when not in use. Si5330F/G/H/J Single-ended Devices. This is one of the single-ended CLK0 outputs. Both CLK0A and CLK0B single-ended outputs are in phase. Refer to AN408 for interfacing and termination details. Leave unconnected when not is use.
23	RSVD_GND			Ground. Must be connected to system ground.
24	VDD	VDD	Supply	Core Supply Voltage. The device operates from a 1.8, 2.5, or 3.3 V supply. A 0.1 $\mu$ F bypass capacitor should be located very close to this pin.
GND PAD	GND	GND	Supply	<b>Ground Pad.</b> This is main ground connection for this device. It is located at the bottom center of the package. Use as many vias as possible to connect this pad to the main ground plane. The device will not function as specified unless this ground pad is properly connected to ground.



# 6. Orderable Part Numbers and Device Functionality

Part Number <sup>1,2</sup>	Input Signal Format	Output Signal Format	Number of Outputs	Frequency Range
LVPECL Buffers				
Si5330A-A00200-GM	Differential	3.3 V LVPECL	4	5 to 710 MHz
Si5330A-A00202-GM	Differential	2.5 V LVPECL	4	5 to 710 MHz
LVDS Buffers				
Si5330B-A00204-GM	Differential	3.3 V LVDS	4	5 to 710 MHz
Si5330B-A00205-GM	Differential	2.5 V LVDS	4	5 to 710 MHz
Si5330B-A00206-GM	Differential	1.8 V LVDS	4	5 to 710 MHz
HCSL Buffers			1	
Si5330C-A00207-GM	Differential	3.3 V HCSL	4	5 to 250 MHz
Si5330C-A00208-GM	Differential	2.5 V HCSL	4	5 to 250 MHz
Si5330C-A00209-GM	Differential	1.8 V HCSL	4	5 to 250 MHz
CMOS Buffers				
Si5330F-A00214-GM	Single-Ended	3.3 V CMOS	8	5 to 200 MHz
Si5330F-A00215-GM	Single-Ended	2.5 V CMOS	8	5 to 200 MHz
Si5330F-A00216-GM	Single-Ended	1.8 V CMOS	8	5 to 200 MHz
CMOS Buffers (Differential In	put)			
Si5330G-A00217-GM	Differential	3.3 V CMOS	8	5 to 200 MHz
Si5330G-A00218-GM	Differential	2.5 V CMOS	8	5 to 200 MHz
Si5330G-A00219-GM	Differential	1.8 V CMOS	8	5 to 200 MHz
SSTL Buffers (Differential Inp	ut)		•	
Si5330H-A00220-GM	Differential	3.3 V SSTL	8	5 to 350 MHz
Si5330H-A00221-GM	Differential	2.5 V SSTL	8	5 to 350 MHz
Si5330H-A00222-GM	Differential	1.8 V SSTL	8	5 to 350 MHz
HSTL Buffers (Differential Inp	out)		1	•
Si5330J-A00223-GM	Differential	1.5 V HSTL	8	5 to 350 MHz
LVPECL Buffers (Single-Ende	d Input)		1	
Si5330K-A00224-GM	Single-Ended	3.3 V LVPECL	4	5 to 350 MHz
Si5330K-A00226-GM	Single-Ended	2.5 V LVPECL	4	5 to 350 MHz

## Table 11. Order Numbers and Device Functionality

Notes:

1. Custom configurations with mixed output types are also available. Please contact the factory for ordering details.

2. Add an "R" to the part number to specify tape and reel shipment media. When specifying non-tape-and-reel shipment media, contact your sales representative for more information.



Part Number <sup>1,2</sup>	Input Signal Format	Output Signal Format	Number of Outputs	Frequency Range
LVDS Buffers (Single-Ended	input)			
Si5330L-A00228-GM	Single-Ended	3.3 V LVDS	4	5 to 350 MHz
Si5330L-A00229-GM	Single-Ended	2.5 V LVDS	4	5 to 350 MHz
Si5330L-A00230-GM	Single-Ended	1.8 V LVDS	4	5 to 350 MHz
HCSL Buffers (Single-Ended	Input)			
Si5330M-A00231-GM	Single-Ended	3.3 V HCSL	4	5 to 250 MHz
Si5330M-A00232-GM	Single-Ended	2.5 V HCSL	4	5 to 250 MHz
Si5330M-A00233-GM	Single-Ended	1.8 V HCSL	4	5 to 250 MHz
Notos:	•		•	•

## Table 11. Order Numbers and Device Functionality (Continued)

Notes:

1. Custom configurations with mixed output types are also available. Please contact the factory for ordering details.

2. Add an "R" to the part number to specify tape and reel shipment media. When specifying non-tape-and-reel shipment media, contact your sales representative for more information.



## 7. Package Outline: 24-Lead QFN

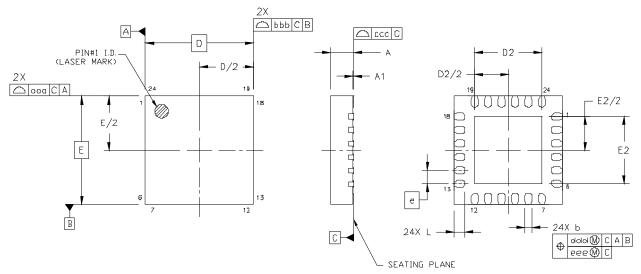


Figure 4. 24-Lead Quad Flat No-Lead (QFN)

Dimension	Min	Nom	Мах	
А	0.80	0.85	0.90	
A1	0.00	0.02	0.05	
b	0.18	0.25	0.30	
D		4.00 BSC.		
D2	2.35	2.50	2.65	
е	0.50 BSC.			
E	4.00 BSC.			
E2	2.35	2.50	2.65	
L	0.30	0.40	0.50	
aaa		0.10		
bbb	0.10			
CCC	0.08			
ddd	0.10			
eee	0.05			

#### Table 12. Package Dimensions

#### Notes:

- 1. All dimensions shown are in millimeters (mm) unless otherwise noted.
- 2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
- 3. This drawing conforms to the JEDEC Outline MO-220, variation VGGD-8.
- **4.** Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.
- 5. J-STD-020 MSL rating: MSL3.
- 6. Terminal base alloy: Cu.
- 7. Terminal plating/grid array material: Au/NiPd.
- 8. For more packaging information, go to www.silabs.com/support/quality/pages/RoHSInformation.aspx.



## 8. Recommended PCB Layout

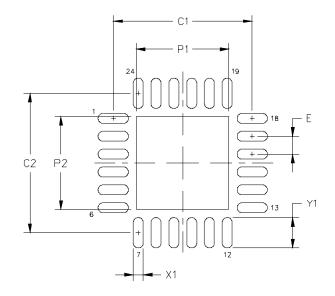


Table 13. PCB Land Pattern

Dimension	Min	Nom	Max		
P1	2.50	2.55	2.60		
P2	2.50	2.55	2.60		
X1	0.20	0.25	0.30		
Y1	0.75	0.80	0.85		
C1		3.90			
C2	3.90				
E		0.50			
Notes:					

#### General

- 1. All dimensions shown are in millimeters (mm) unless otherwise noted.
- 2. Dimensioning and Tolerancing per ANSI Y14.5M-1994 specification.
- 3. This Land Pattern Design is based on the IPC-7351 guidelines.
- 4. Connect the center ground pad to a ground plane with no less than five vias to a ground plane that is no more than 20 mils below it. Via drill size should be no smaller than 10 mils. A longer distance to the ground plane is allowed if more vias are used to keep the inductance from increasing.

#### Solder Mask Design

5. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 μm minimum, all the way around the pad.

#### **Stencil Design**

- 6. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
- 7. The stencil thickness should be 0.125 mm (5 mils).
- 8. The ratio of stencil aperture to land pad size should be 1:1 for all perimeter pins.
- 9. A 2x2 array of 1.0 mm square openings on 1.25 mm pitch should be used for the center ground pad.

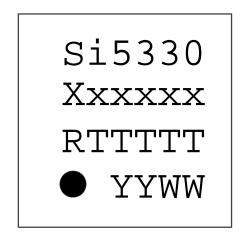
#### Card Assembly

- **10.** A No-Clean, Type-3 solder paste is recommended.
- 11. The recommended card reflow profile is per the JEDEC/IPC J-STD-020C specification for Small Body Components.



# 9. Top Marking

## 9.1. Si5330 Top Marking



## 9.2. Top Marking Explanation

Mark Method:	Laser	Laser				
Line 1 Marking:	Device Part Number	Si5330				
Line 2 Marking:	X = Frequency and configuration code. xxxxx = Input and output format configu- ration code. See "6. Orderable Part Numbers and Device Functionality" on page 14 for more information.	Хххххх				
Line 3 Marking:	R = Product revision (A). TTTTT = Manufacturing trace code.	RTTTT				
Line 4 Marking:	Pin 1 indicator.	Circle with 0.5 mm diameter; left-justified				
	YY = Year. WW = Work week. Characters correspond to the year and work week of package assembly.	YYWW				



# DOCUMENT CHANGE LIST

## **Revision 0.1 to Revision 0.2**

- Clarified documentation to reflect that Pin 19 is OEB (OE Enable Low).
- Updated Table 4, "Jitter Specifications" on page 7.

## Revision 0.2 to Revision 0.3

- Major editorial updates to improve clarity.
- Updated "Additive Jitter" Specification Table.
- Updated "Core Supply Current" Specification in Table 2.
- Removed the Low-Power LVPECL output options from the ordering table in section 6.
- Removed D/E ordering options.

## **Revision 0.3 to Revision 0.35**

- Typo of 150 ps on front page changed to 150 fs.
- Updated PCB layout notes.
- Added no ac coupling for LVDS outputs.
- Changed input rise/fall time spec to 2 ns.

## Revision 0.35 to Revision 1.0

- Added maximum junction temperature specification to Table 9 on page 8.
- Added minimum and maximum duty cycle specifications to Table 4 on page 5.
- Updated Table 3, "Performance Characteristics," on page 5.
  - Added maximum propagation delay spec (4 ns).
  - Added test condition to t<sub>LOS B</sub> in Table 3 on page 5.
  - Removed reference to frequency in Output-Output Skew.
- Updated Table 4, "Input and Output Clock Characteristics," on page 5.
  - Input voltage (max) changed "3.63" to "VDD"
  - Input voltage swing (max) change "3.63" with "-".
- Added Table 6, "Output Control Pins (LOS)," on page 7.
- Added tape and reel ordering information to "6. Orderable Part Numbers and Device Functionality" on page 14.
- Added "9. Top Marking" on page 18.



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